



National Accreditation Board for
Testing and Calibration Laboratories

CERTIFICATE OF ACCREDITATION

BNN COMMUNICATION ENGINEERS PVT.LTD. (EMR DIV)

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2017

**"General Requirements for the Competence of Testing &
Calibration Laboratories"**

for its facilities at

33/33, INDUSTRIAL AREA, SITE 2, LONI ROAD, MOHAN NAGAR, SAHIBABAD, GHAZIABAD, UTTAR
PRADESH, INDIA

in the field of

TESTING

Certificate Number: TC-8196

Issue Date: 08/09/2024

Valid Until:

07/09/2026

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the relevant requirements of NABL.

(To see the scope of accreditation of this laboratory, you may also visit NABL website www.nabl-india.org)

Name of Legal Entity: BNN COMMUNICATION ENGINEERS PRIVATE LIMITED

Signed for and on behalf of NABL



N. Venkateswaran
Chief Executive Officer



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : BNN COMMUNICATION ENGINEERS PVT.LTD. (EMR DIV), 33/33, INDUSTRIAL AREA, SITE 2, LONI ROAD, MOHAN NAGAR, SAHIBABAD, GHAZIABAD, UTTAR PRADESH, INDIA

Accreditation Standard ISO/IEC 17025:2017

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Validity 08/09/2024 to 07/09/2026 **Last Amended on** 14/09/2024

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
Site Testing				
1	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber	Free Space Normalised Site Attenuation (FSNSA) FAR Configuration	CISPR 16-1-4:2019+AMD1:2020+AM D2:2023 CSV
2	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber/Semi Anechoic Chamber / Open Area Test Site	Field Uniformity	IEC 61000-4-3:2020
3	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber/Semi Anechoic Chamber / Open Area Test Site	Site Voltage Standing Wave Ratio (sVSWR)	CISPR 16-1-4, Edition 3.0 (Withdrawn):2010
4	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber/Semi Anechoic Chamber / Open Area Test Site	Site Voltage Standing Wave Ratio (sVSWR)	CISPR 16-1-4+AMD1:2020
5	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber with Ground Plane/Open Area Test Site	ALSE performance validation using Long Wire Antenna Method	IEC/CISPR 25, Edition 5.0:2021
6	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	ANSI C63.4:2014
7	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	ANSI C63.4A:2014
8	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	CISPR 16-1-4:2019+AMD1:2020+AM D2:2023
9	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	NSIL (Normalised Site insertion loss measurement)	CISPR 16-1-4:2019+AMD1:2020+AM D2:2023
10	ELECTRONICS- EMC TEST FACILITY	Semi or Fully Anechoic Chamber/Open Area Test Site	Setup Table Influence (STI) Measurement	CISPR 16-1-4:2019+AMD1:2020+AM D2:2023 CSV
11	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	BS EN 50147-1:1997
12	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	IEEE 299:2006
13	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	MIL Std. 188-125.1,(Appendix A):2005
14	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	MIL Std. 188-125.2,(Appendix A):2005
15	ELECTRONICS- EMC TEST FACILITY	Shielded Enclosure/Cabinet	Shielding Effectiveness	IEC 61000-5-7:2001
16	ELECTRONICS- EMC TEST FACILITY	Shielded Enclosure/Cabinet (0.75 m to 2 m)	Shielding Effectiveness	IEEE 299.1:2013